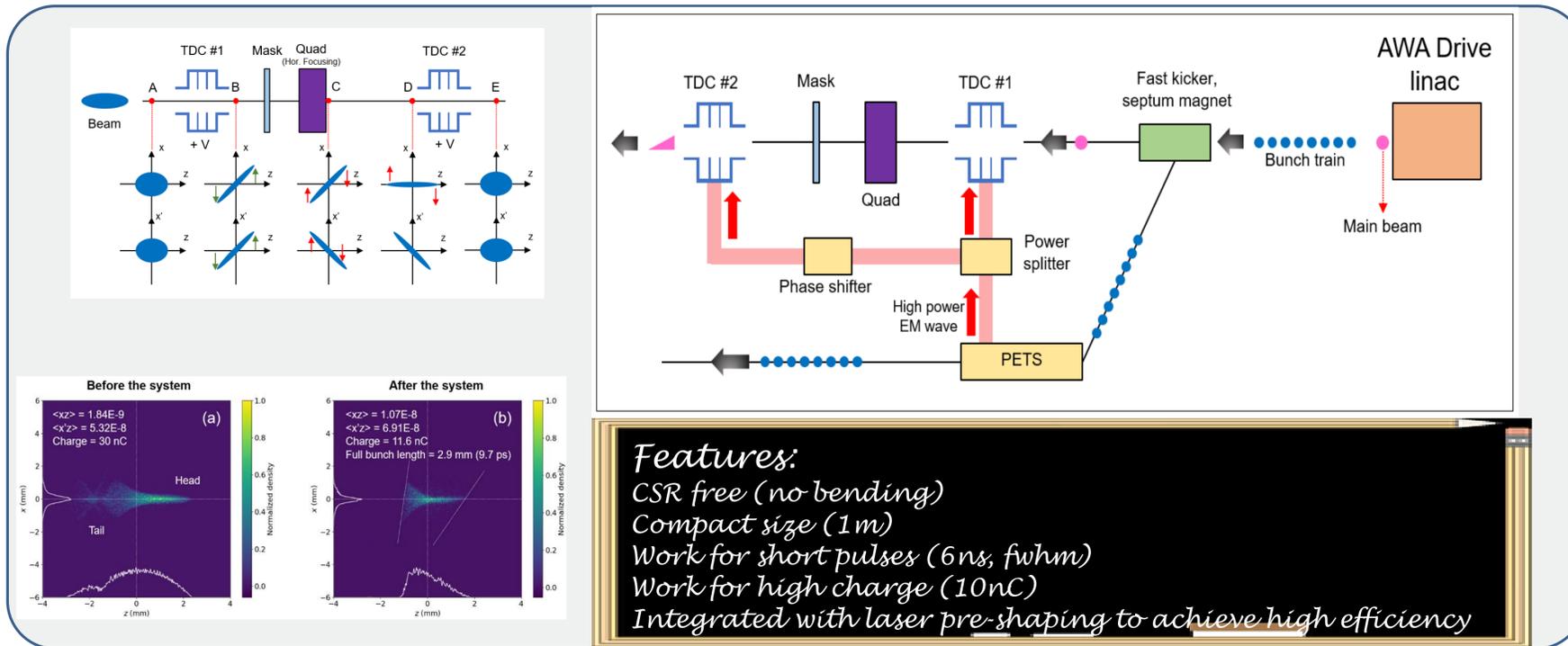
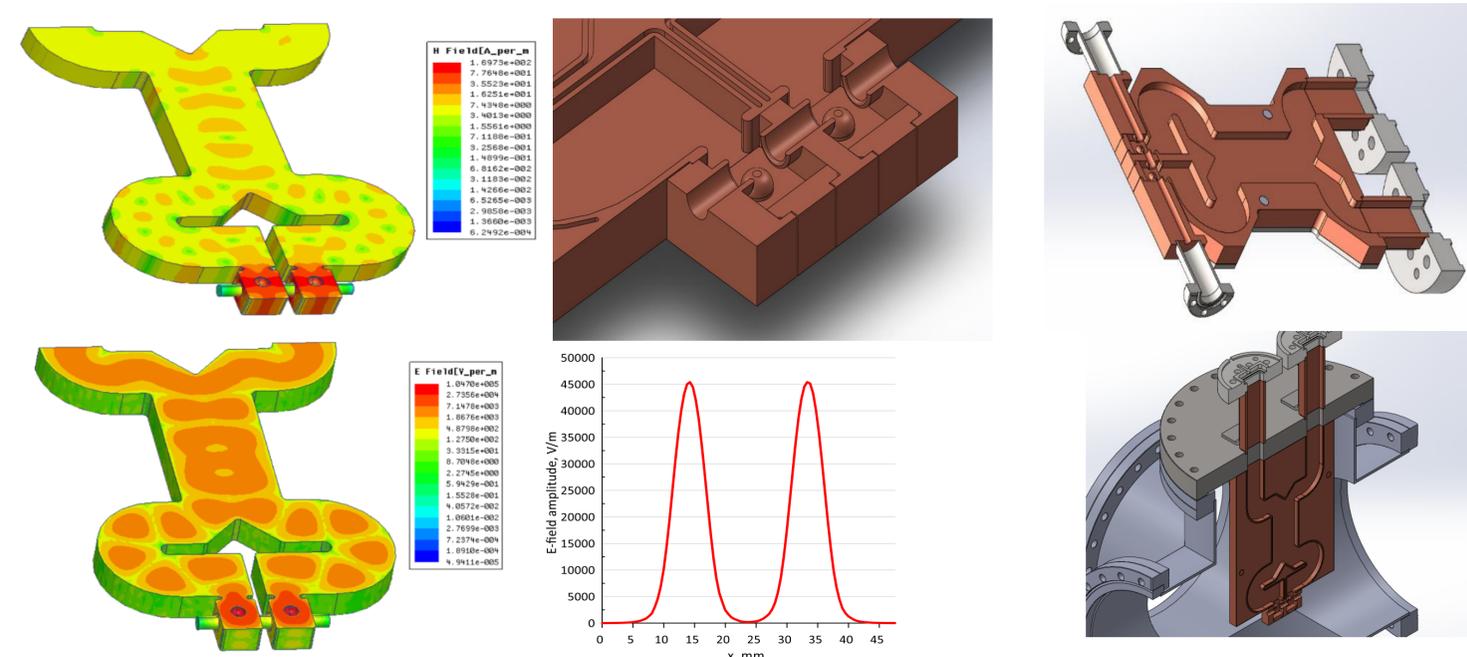


C. Jing, S. Kuzikov, E. Knight, S. Weatherly, S. Kim, P. Piot, E. Wisniewski, S. Doran, J. Power

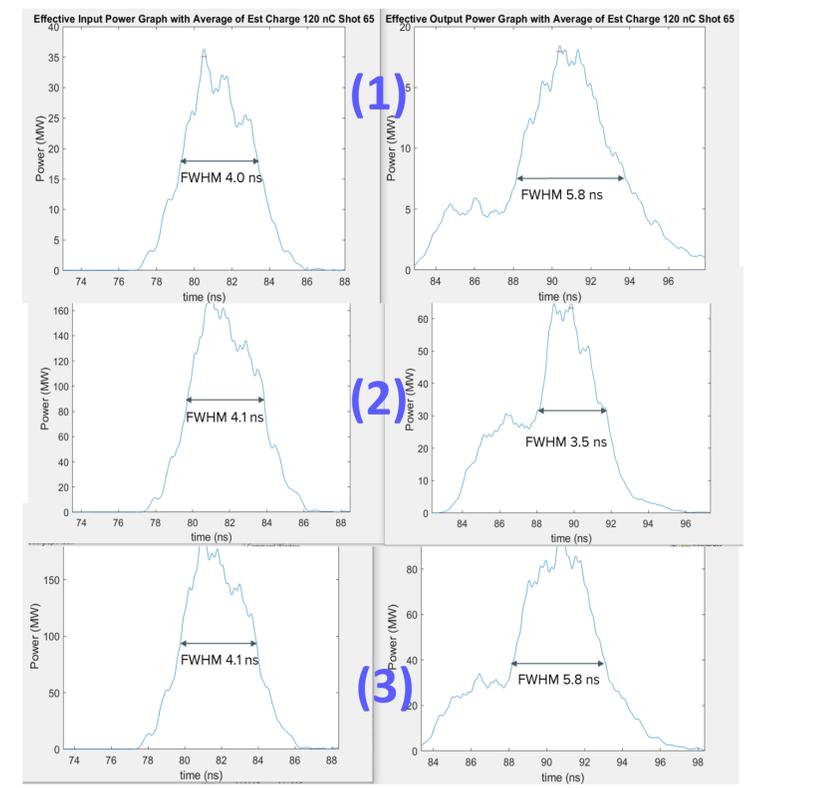
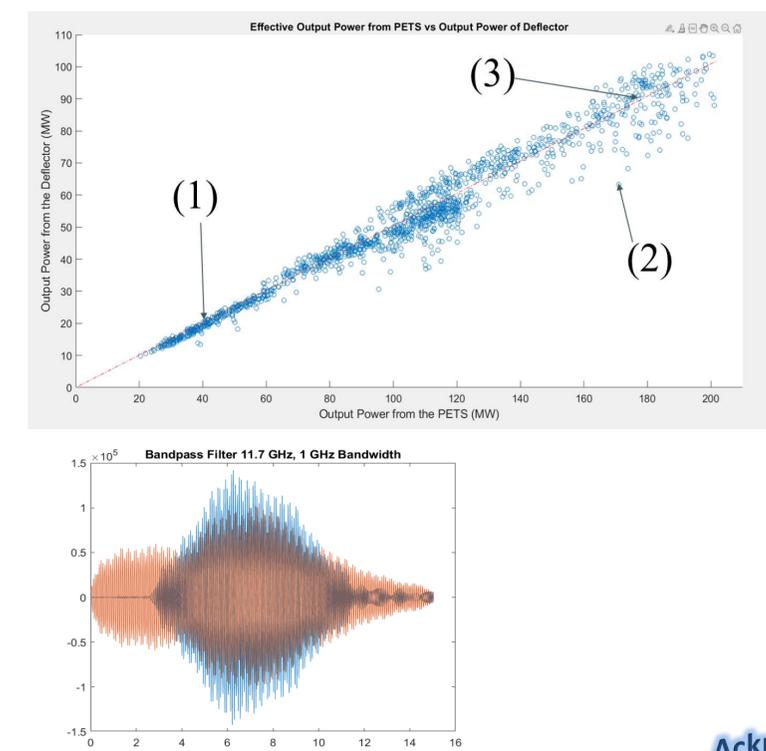
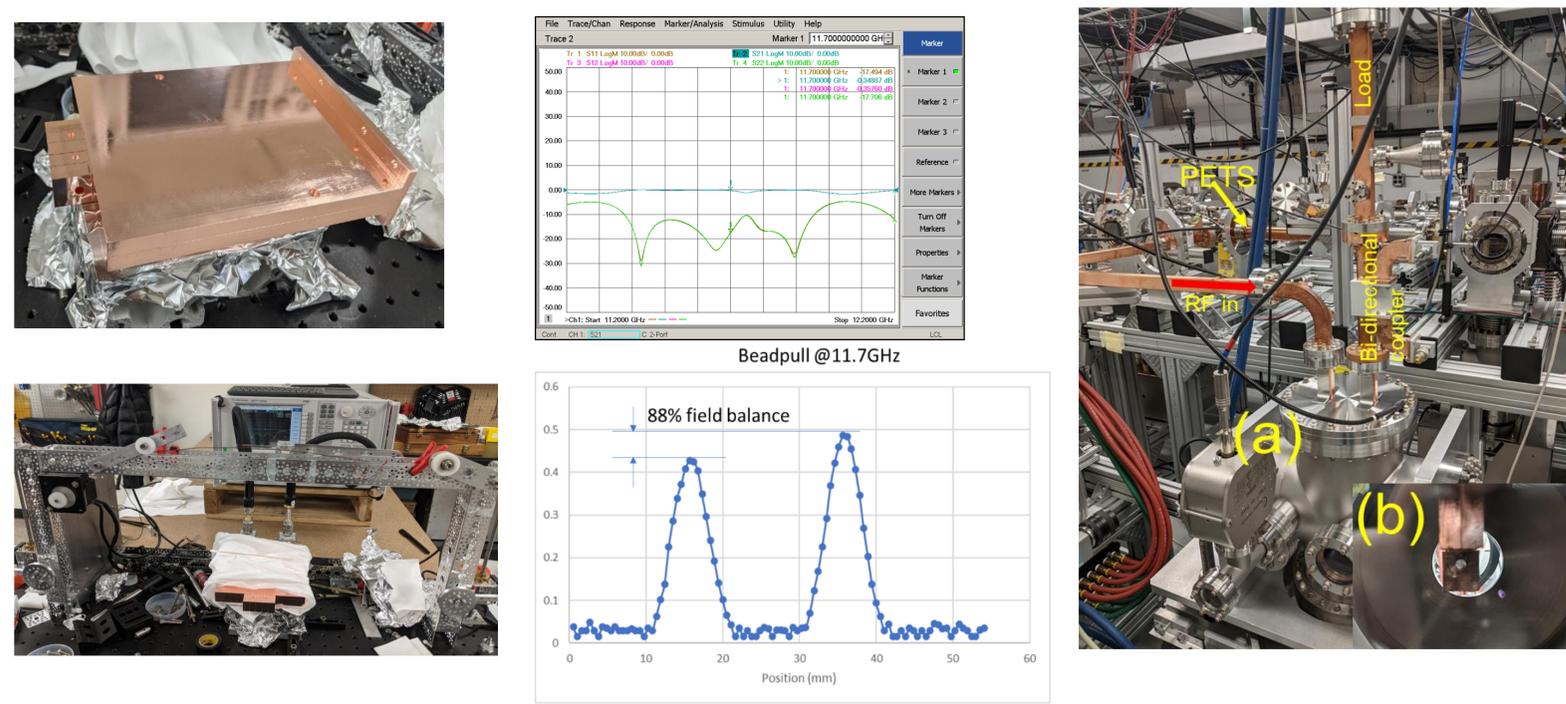
## APPLICATION



## RF AND ENGINEERING DESIGN



## FABRICATION, BENCH MEASUREMENT, & HIGH POWER RF TEST



Acknowledgement